

Fault Detection for Photovoltaic Systems on the Edge

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FH Zentralschweiz

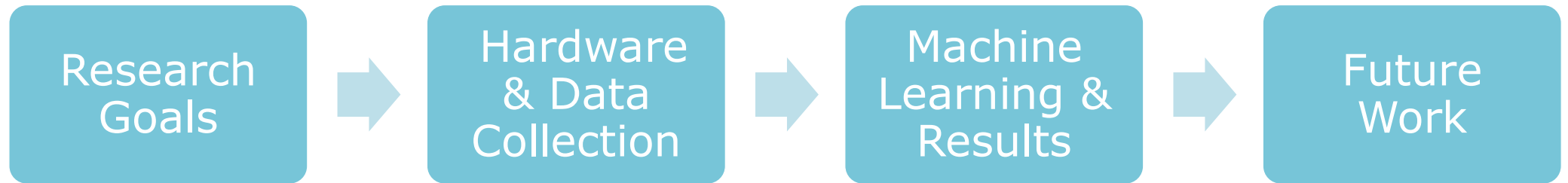




CLEANLINE

PLEASE

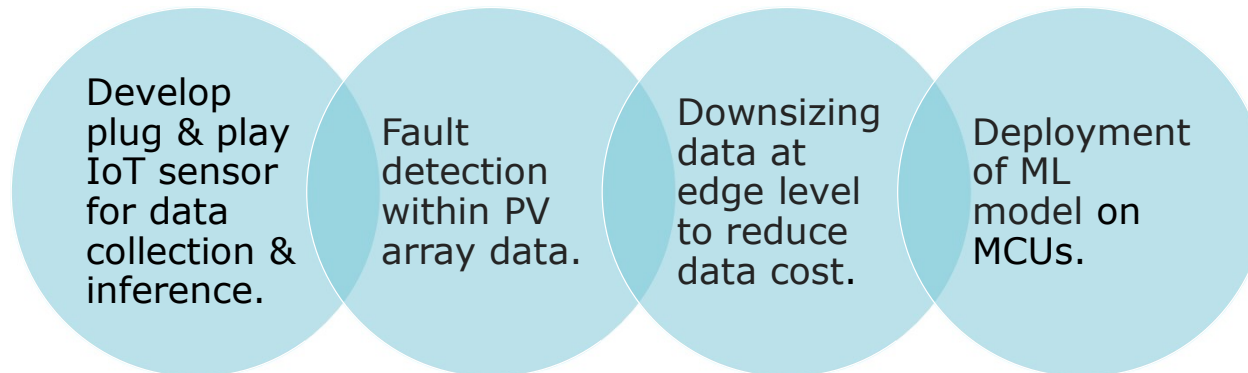
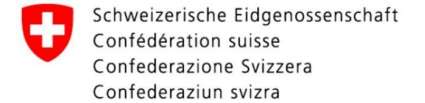
Topics for today



Research Goals

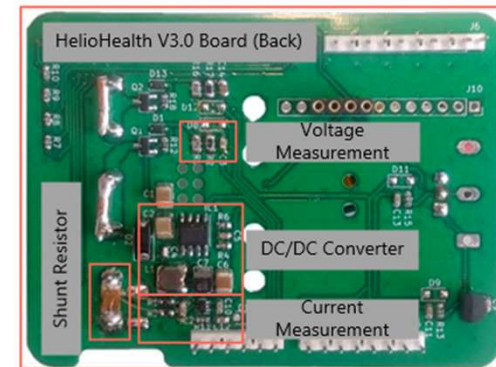
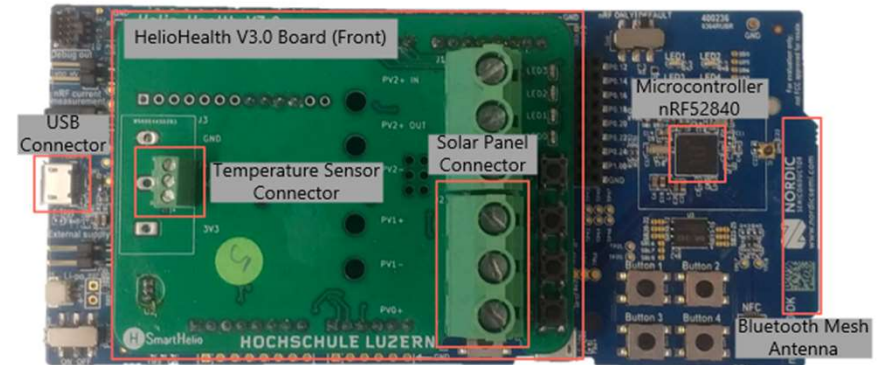
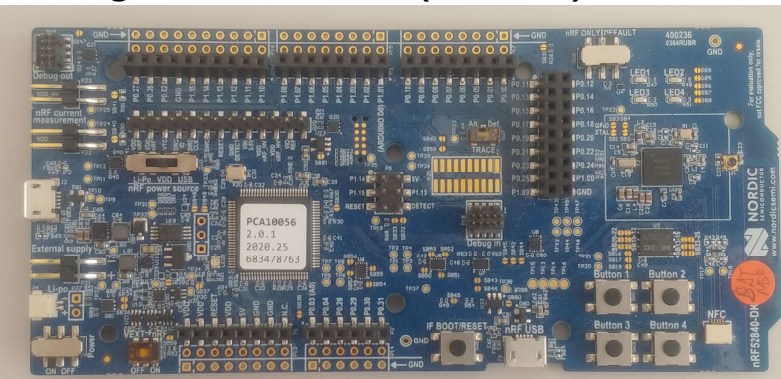


Innosuisse - Swiss Innovation Agency



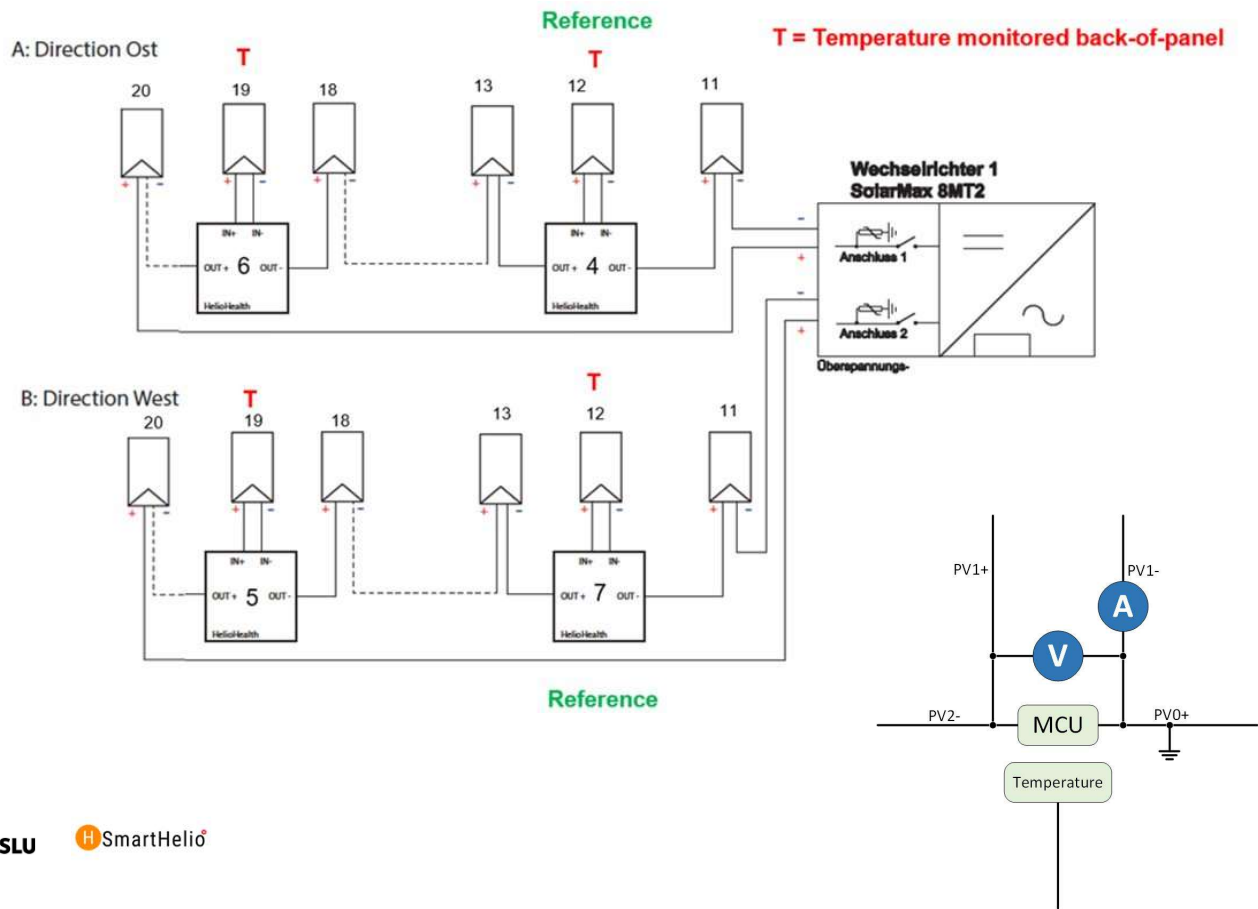
Sensor Hardware

- Scalability: Mesh Communication
- Plug & Play
- Low-cost & low-power
- Nordic Semiconductor nRF52840
- Cortex M4F, 1MB Flash, 256kB RAM
- Integrated BT Mesh (2.4GHz) Transceiver



Measurements:
 -Voltage
 -Current
 -Temperature

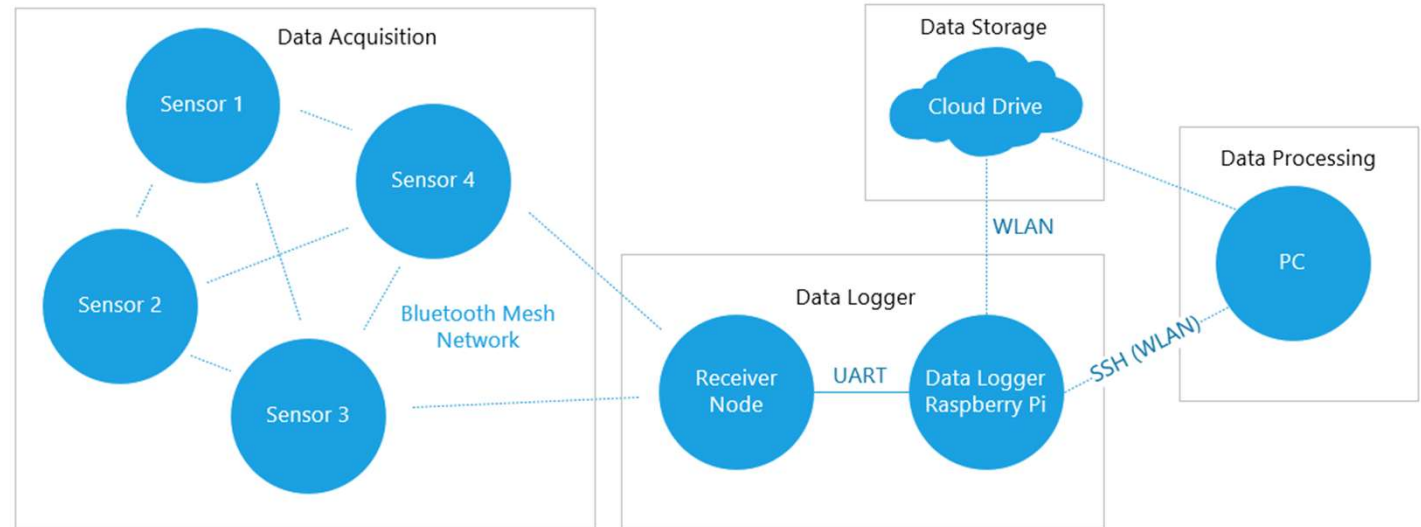
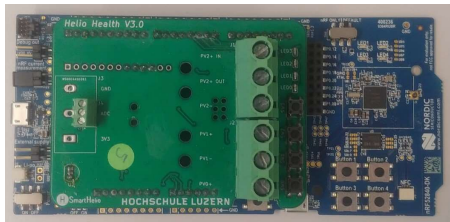
HSLU PV System



Installation



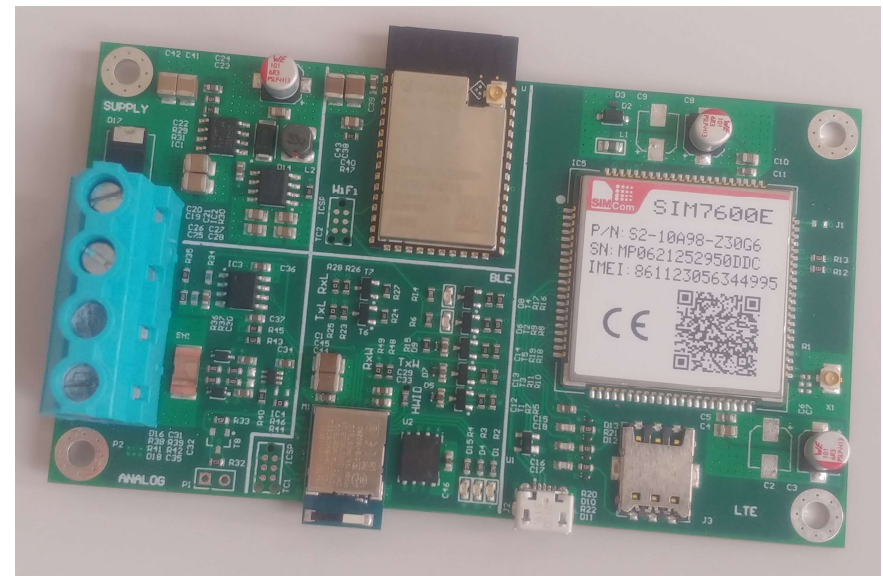
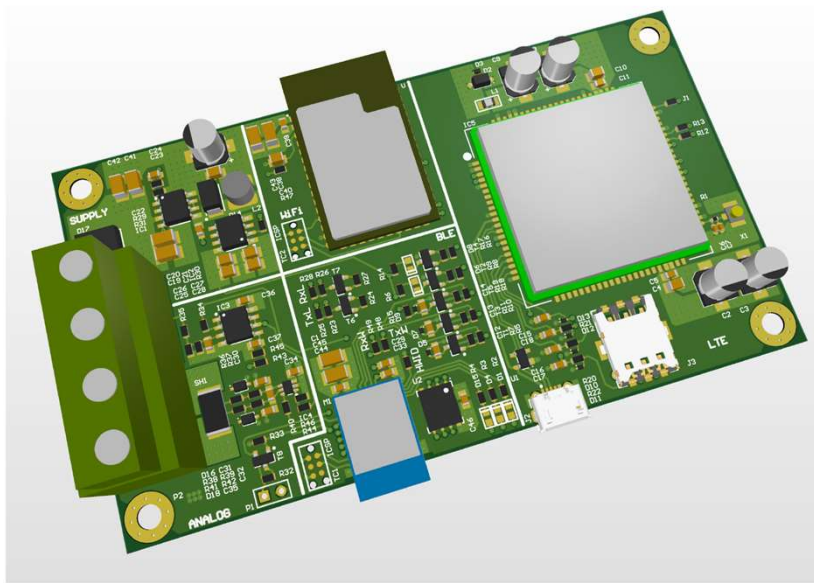
System Architecture for Data Collection for ML



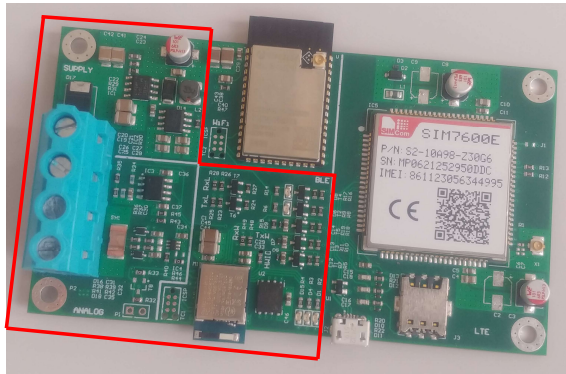
Almost 1 year of data ~10GB



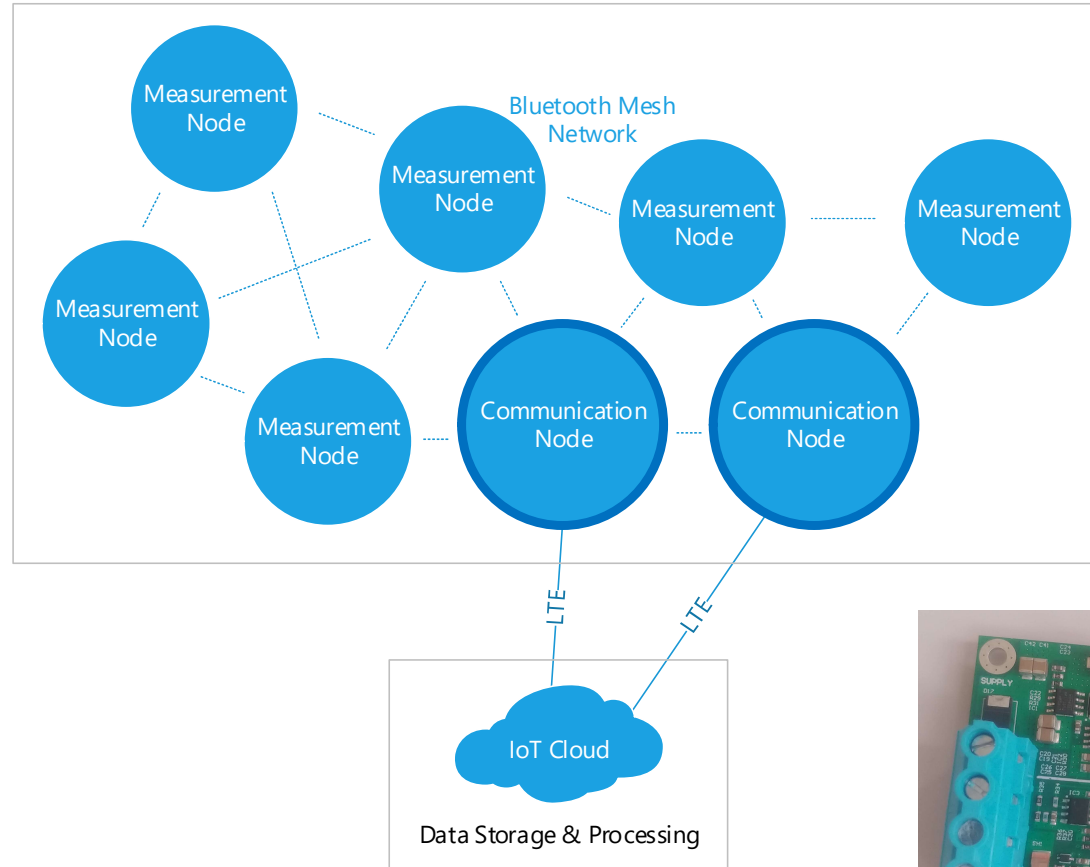
PCB



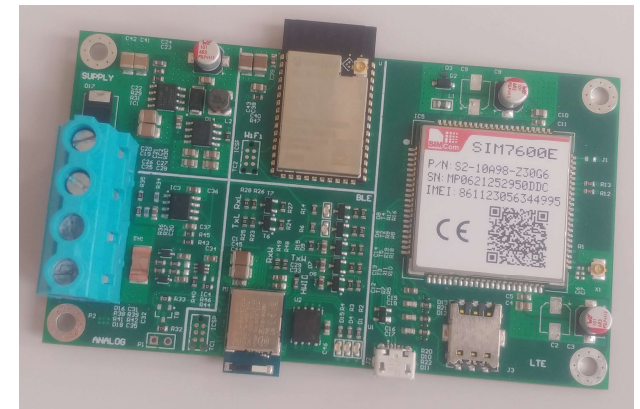
Final Architecture



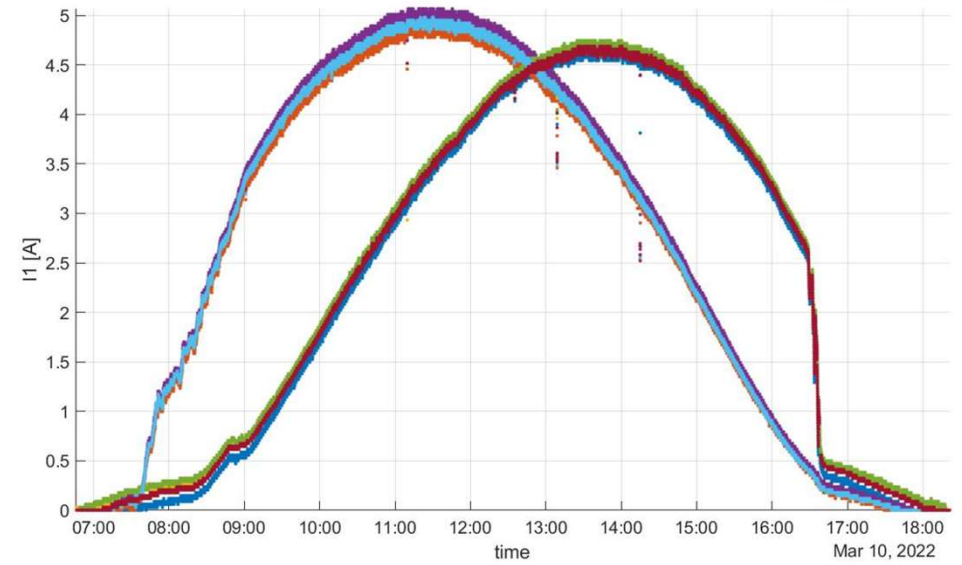
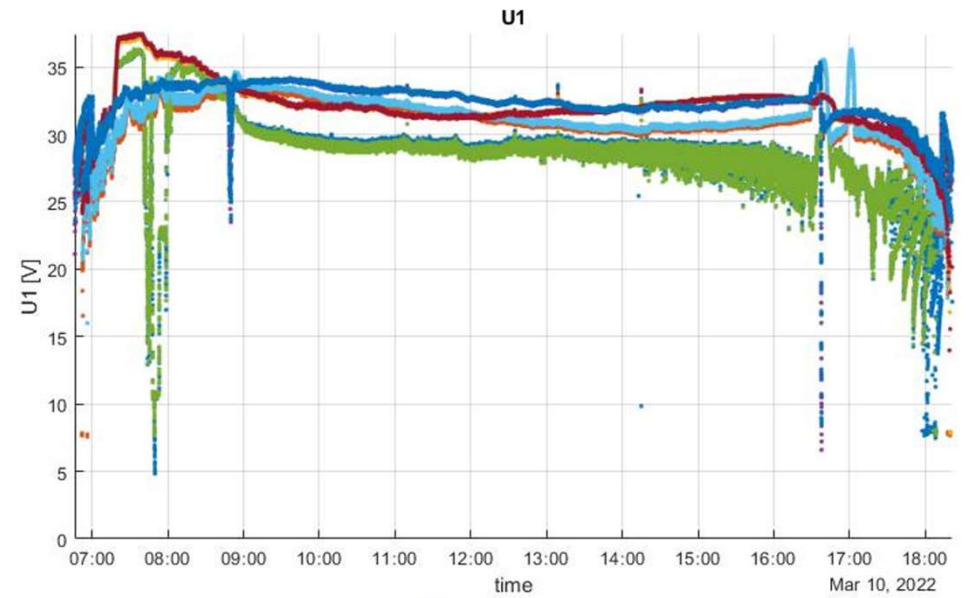
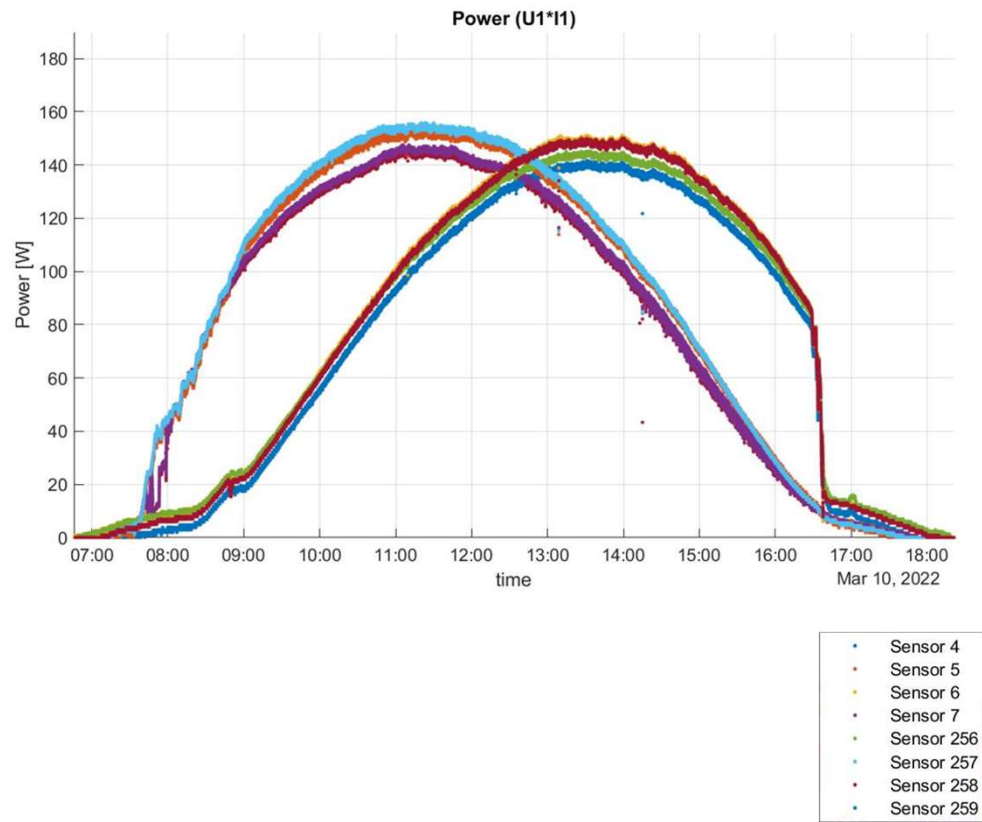
Measurement Nodes:
Bluetooth Mesh



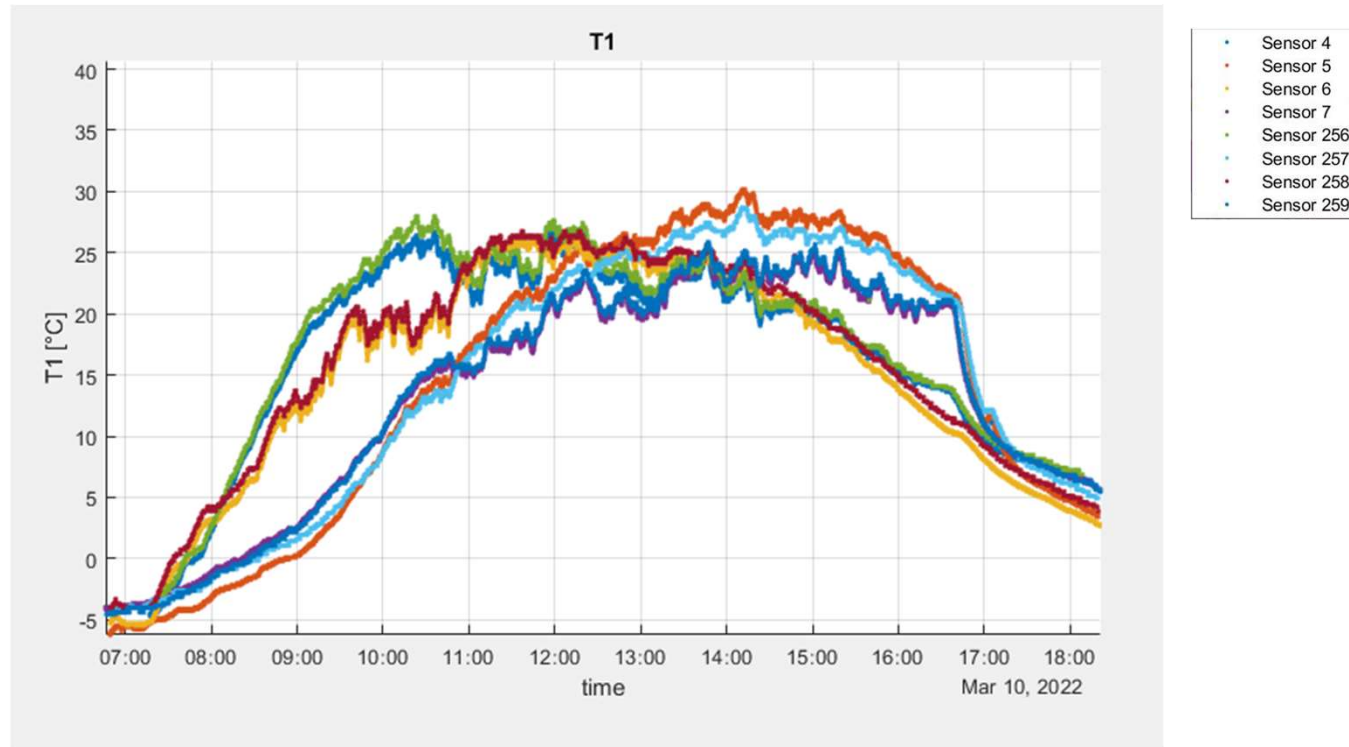
Communication Nodes:
Bluetooth Mesh
+ LTE



Data Sample 10.03.2022



Temperature 10.03.2022



Controlled Fault Application

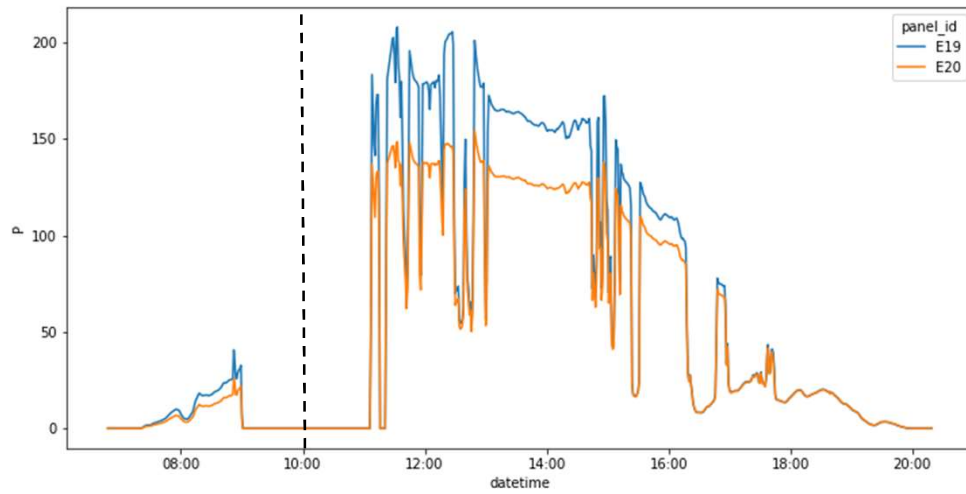
- No Fault
- Connector Failure
- Object Shading
- Partial Soiling
- Partial Shading
- Short Circuit Bypass Diode
- Soiling on Border



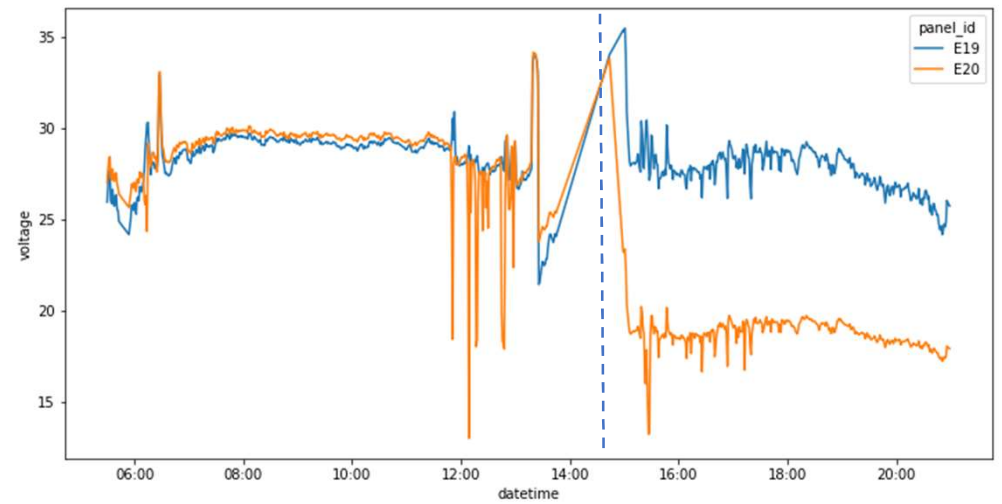
Challenges Hardware & Data Collection

- Powered by solar panel only
- Receiver node placement (Indoors – Blinds to North)
- Cloud communication for global deployment
- Access to array is difficult

Effect of faults on power and voltage characteristics

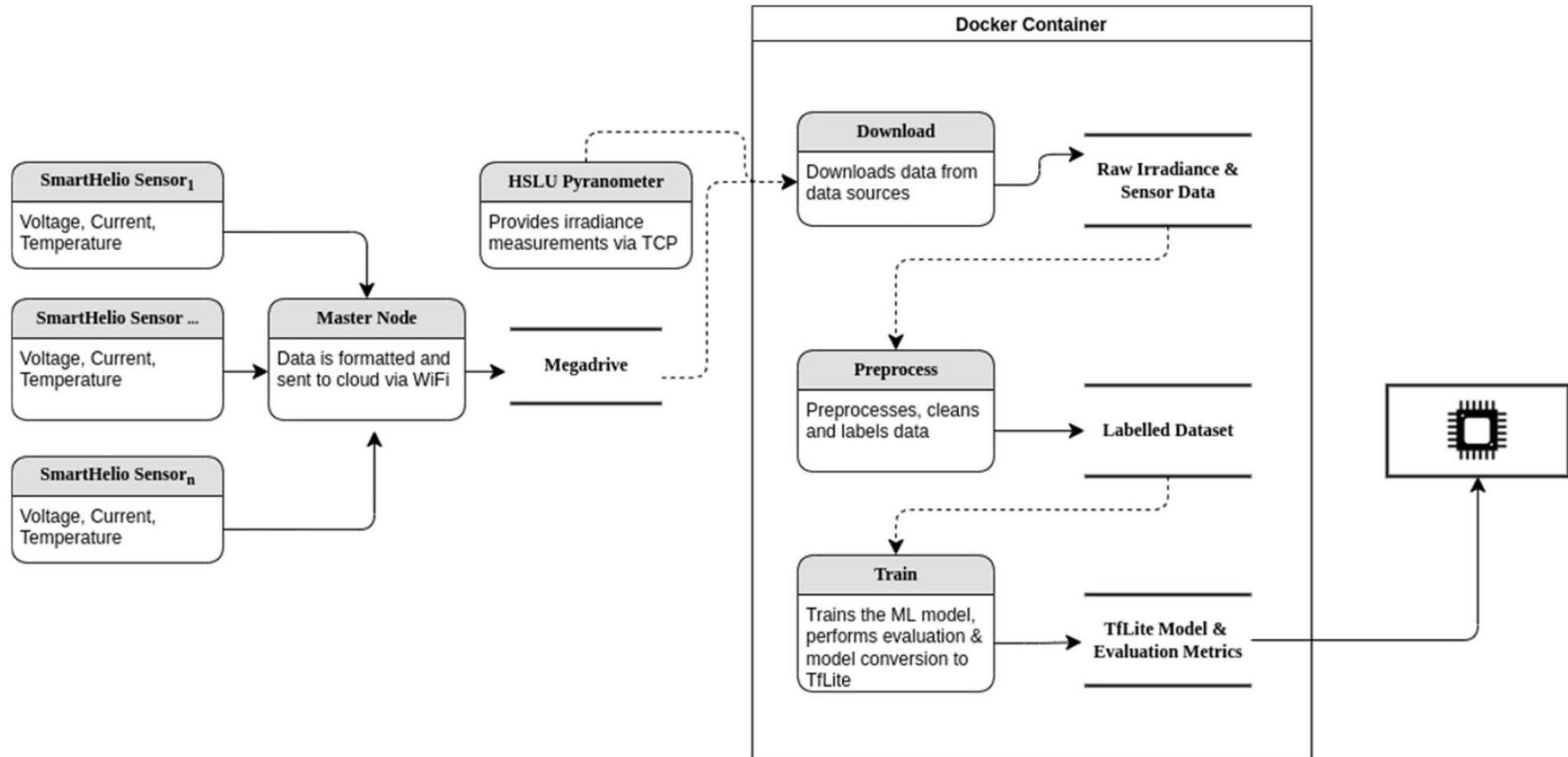


Connector Failure (23.08)



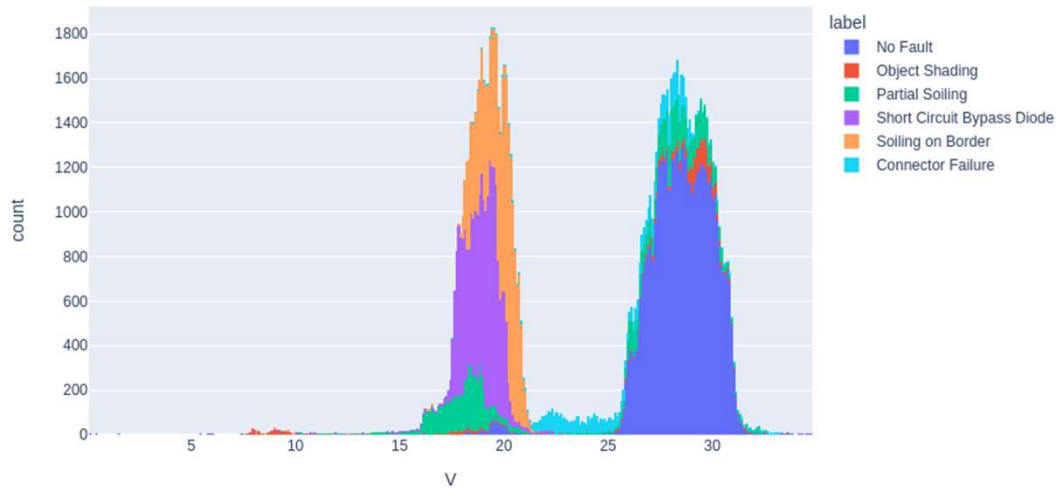
Short Circuit Bypass Diode (05.07)

Machine Learning Pipeline Overview

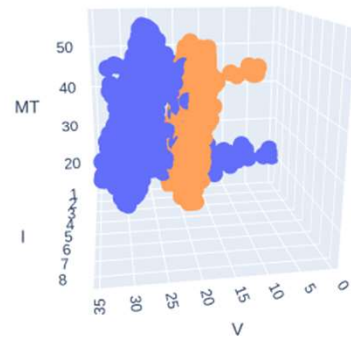
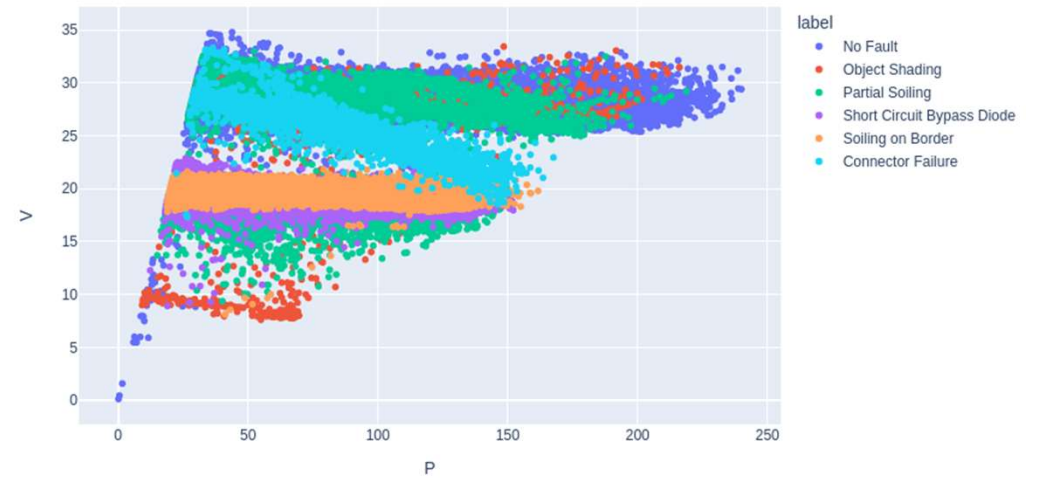


A look at the processed data

Distribution of voltage by fault



Relationship between power and voltage



Input Features

Measured Features

Voltage (V)

Current (I)

Average Global Horizontal Irradiance (G)

Module Temperature in Celsius (MT)

Computed Features

Power (P)

Expected Power (P_{exp})

Expected Current (I_{exp})

Expected Voltage (V_{exp})

Expected Open Circuit Voltage (V_{oc_exp})

Expected Short Circuit Current (I_{sc_exp})

Ratio Features

P / P_{exp}

V / V_{exp}

I / I_{exp}

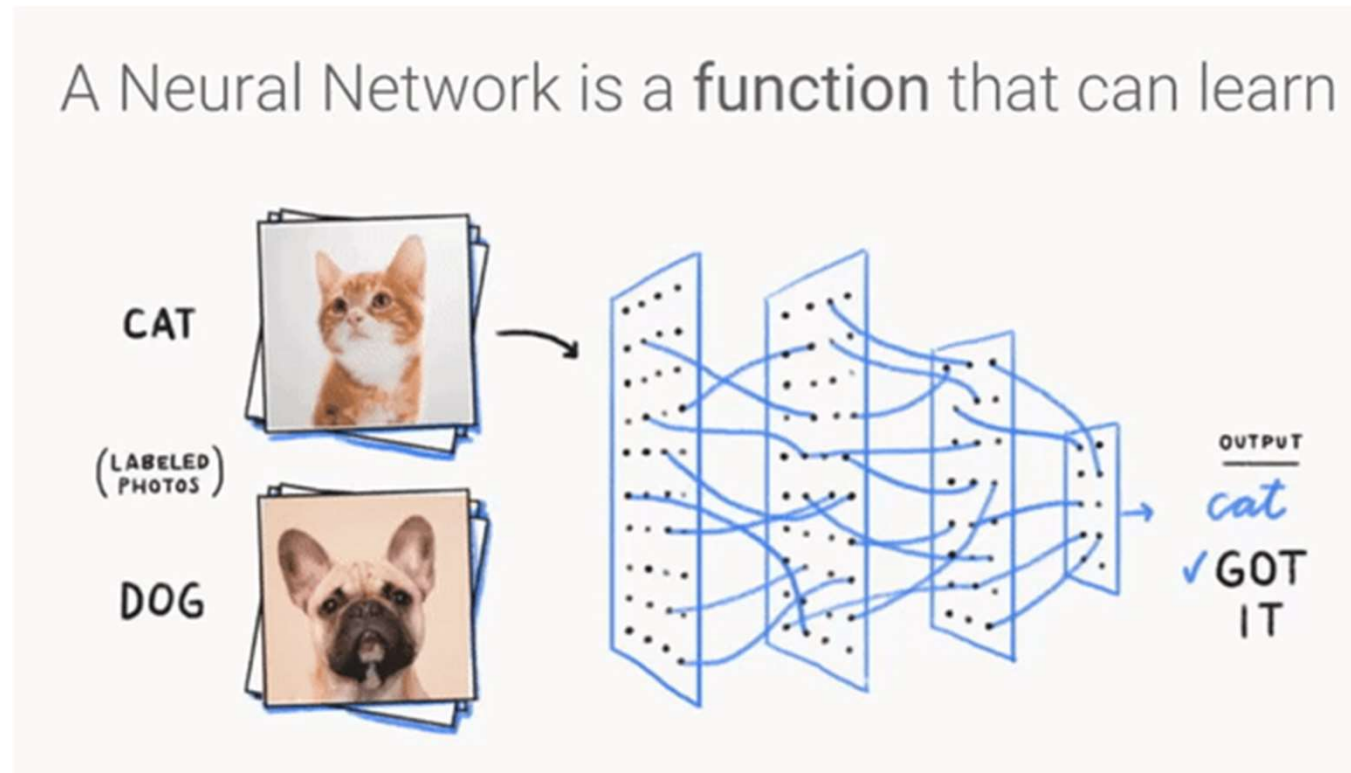
V / V_{oc_ref}

I / I_{sc_ref}

V / V_{oc_exp}

I / I_{sc_exp}

What is a neural network?



Convolutional Neural Networks for image classification (2D)

Kernel Convolution Example

Input Image

10	10	10	10	10	10
10	10	10	10	10	10
10	10	10	10	10	10
0	0	0	0	0	0
0	0	0	0	0	0
0	0	0	0	0	0

Kernel

1	2	1
0	0	0
-1	-2	-1

Feature Map

$*$ $=$

Edge Detection Using Kernel Convolution



Source: Skalski, P. (2021, December 9).

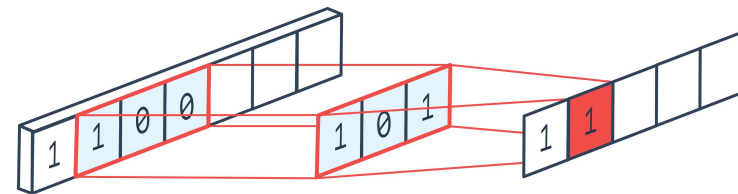
Convolutional Neural Networks for signal processing (1D)

- Neighboring points in timeseries are related, convolution exploits this!

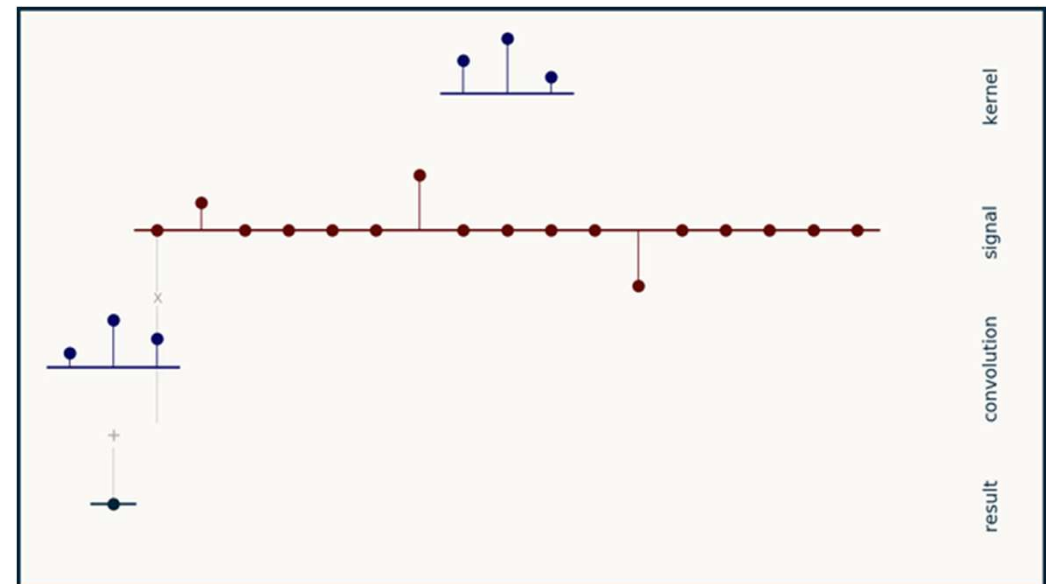
- Finds local patterns that reoccur in the data.

- Models learns different types of patterns (kernels) through backpropagation.

- Goal is to minimise model error (loss function).



Source: Peltarion, P. (2021).



Source: Rohrer, B. (2020).

Model Architectures

Single-minute observations as input

2-layer 1D CNN model with 17 features.

Multi-hour time window as input

6-layer 1D CNN model, with Dropout and MaxPooling inspired by VGG model with only 4 measured features (V, I, G, MT).

Prediction format

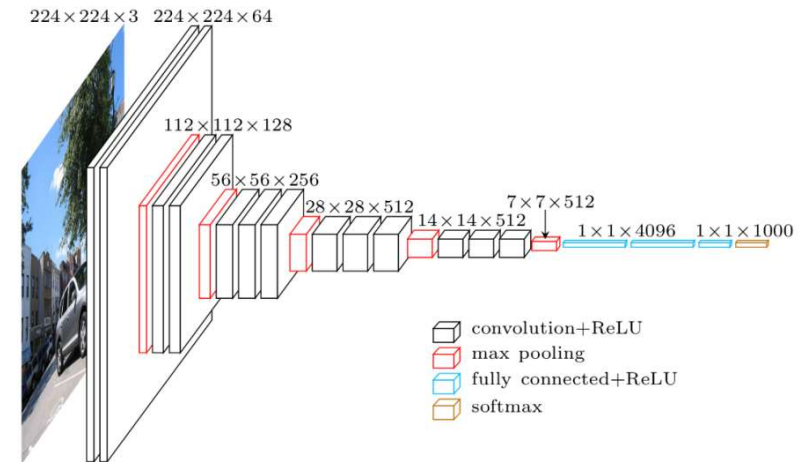
Probability distribution over classes e.g.

[0.08, 0.72, 0.11, 0.09]

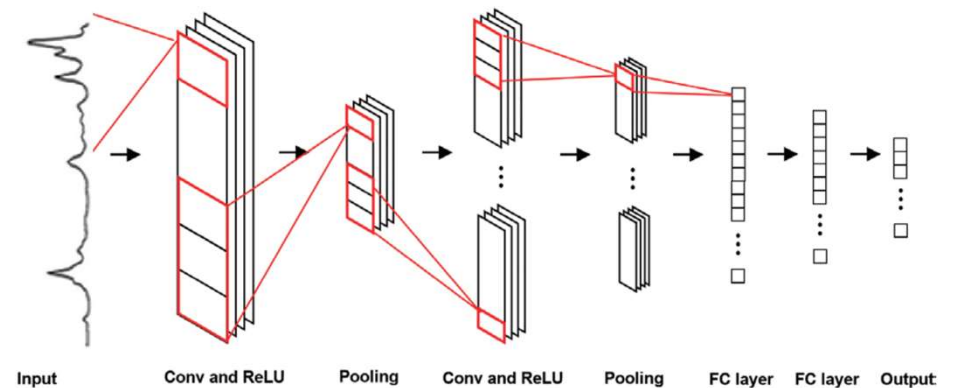
[class 0, class 1, class 2, class 3]

Maximum probability represents class

[0, 1, 0, 0]



Source: Sugata & Yang (2017).

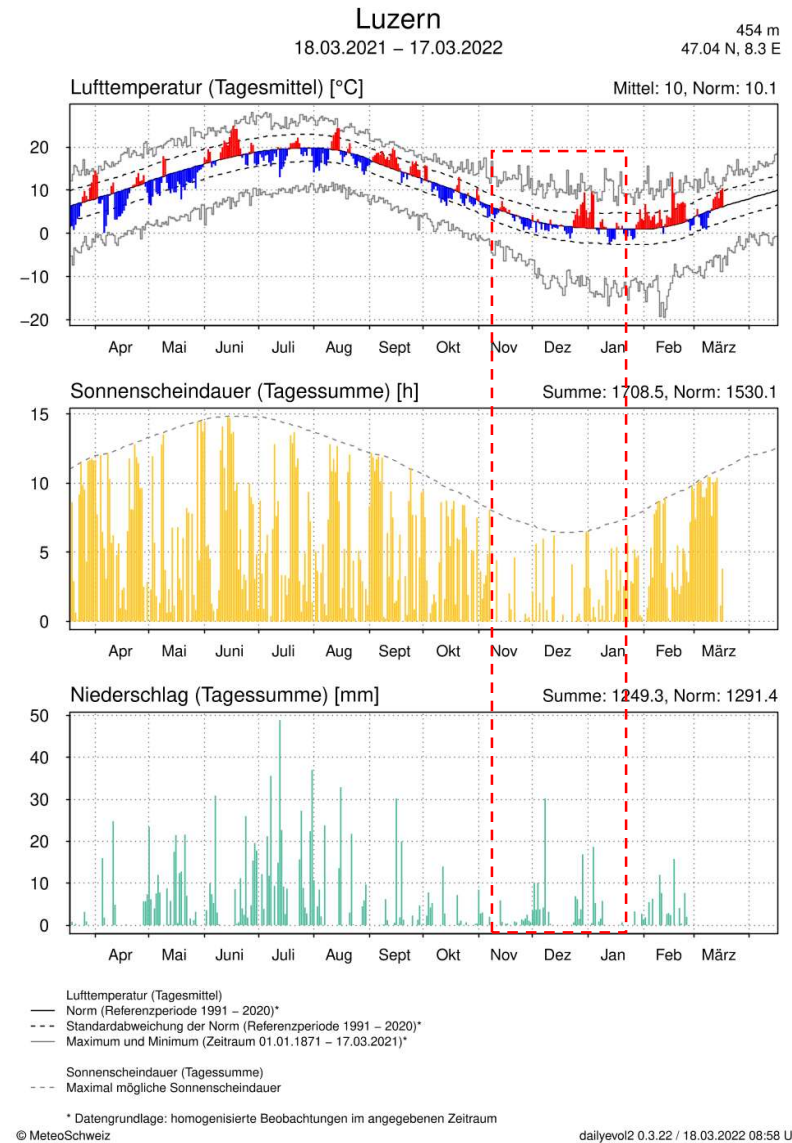
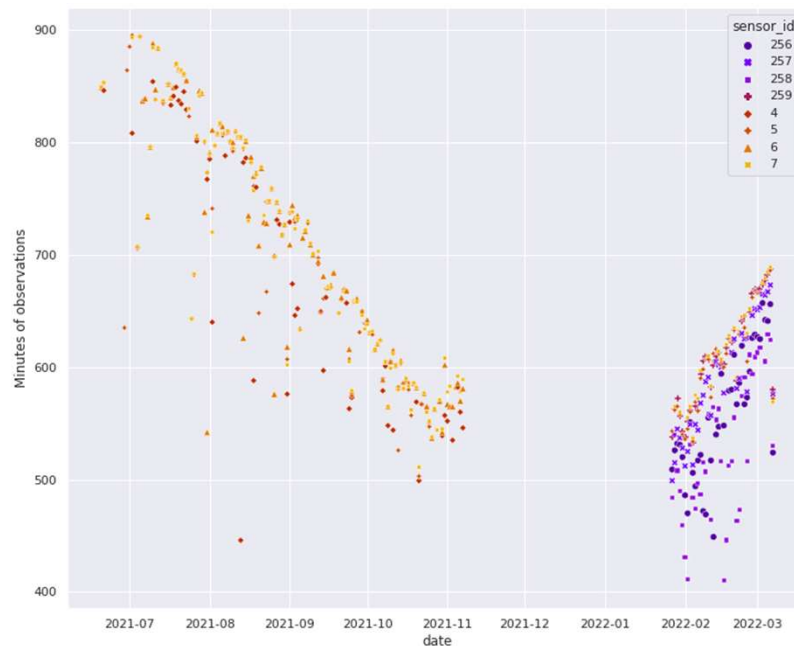


Source: Mozzafari & Tay (2020).

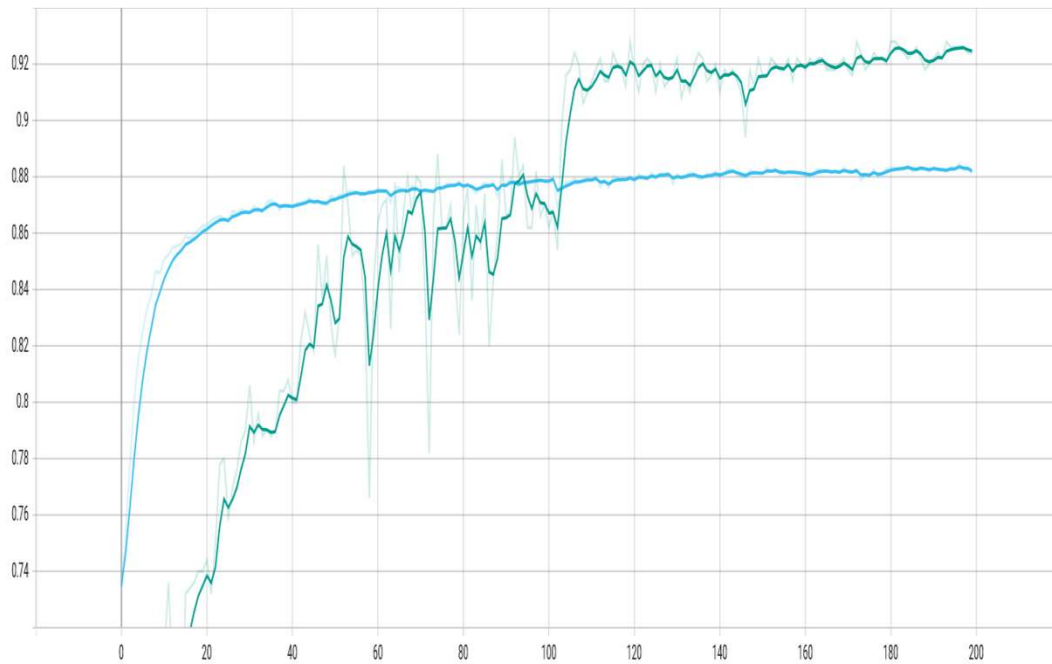
Model Training

Single-minute observations as input
Data selected from May – October 2021.

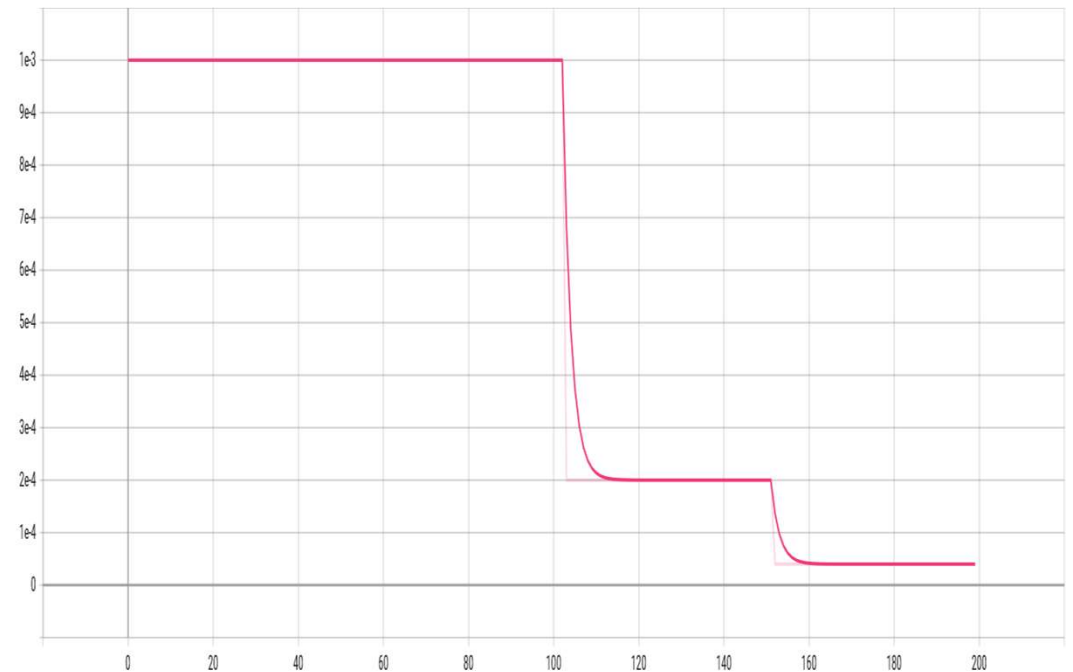
Multi-hour time window as input
Data selected from May – November 2021,
January – March 2022.



Single vs multi-timestamp training accuracy on validation set



Single-timestamp model (blue), Multi-timestamp model (green)



Learning rate reduction during detection of a plateau

Model Evaluation Metrics

Model is evaluated on an unseen test set comprising 20% of the dataset (~82,000 min. Observations).

Evaluation metrics are computed on a per class basis.

$$\text{Accuracy} = \frac{TP + TN}{TP + TN + FP + FN}$$

$$\text{Precision} = \frac{TP}{TP + FP}$$

$$\text{Recall} = \frac{TP}{TP + FN}$$

$$F1 = 2 \cdot \frac{\text{precision} \cdot \text{recall}}{\text{precision} + \text{recall}}$$

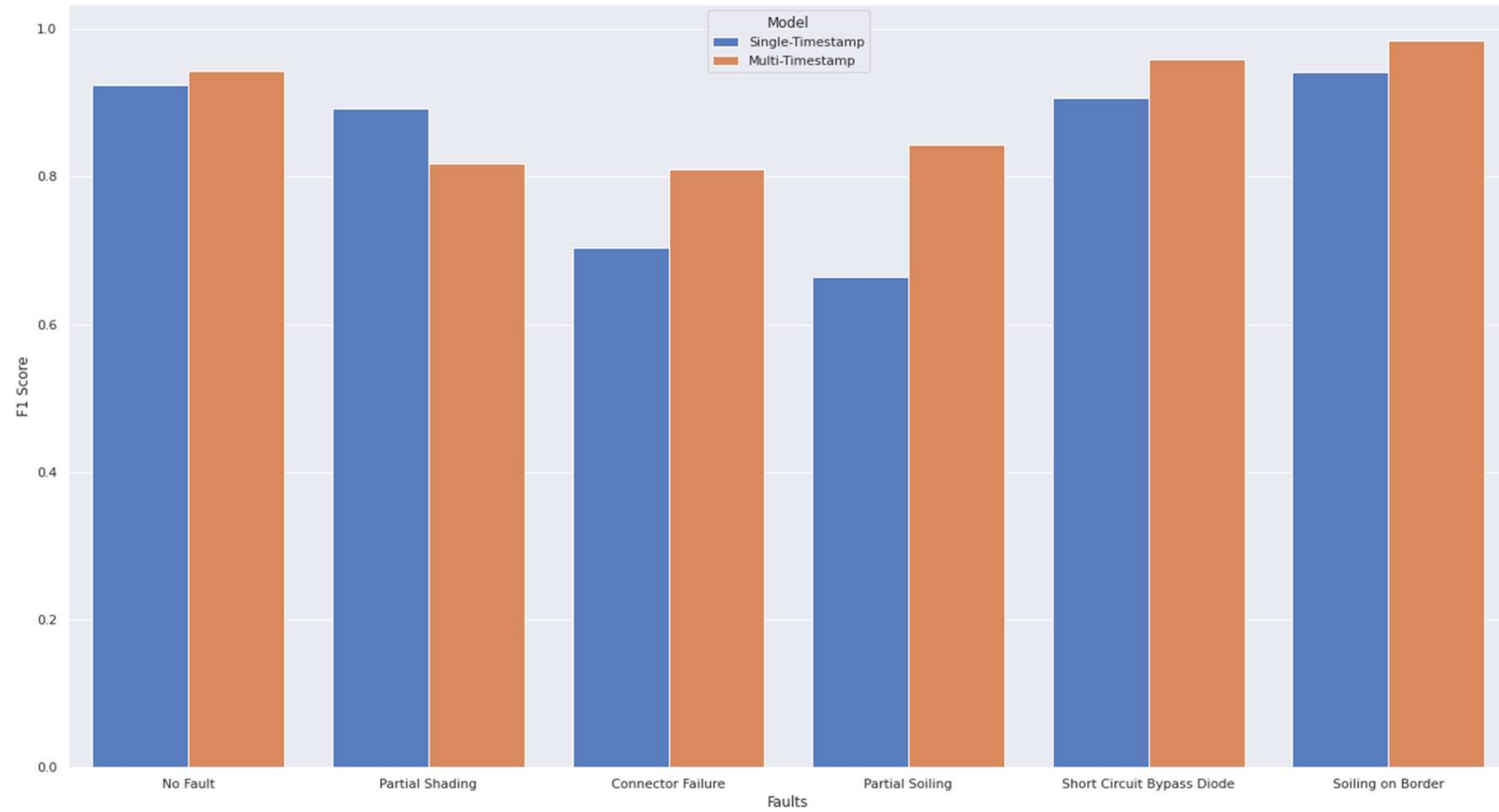
TP = True positive

TN = True negative

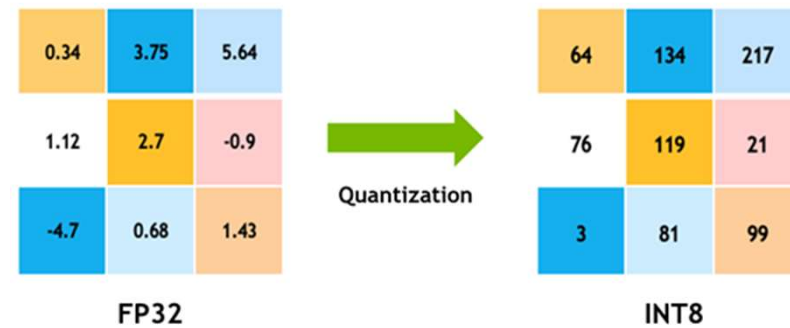
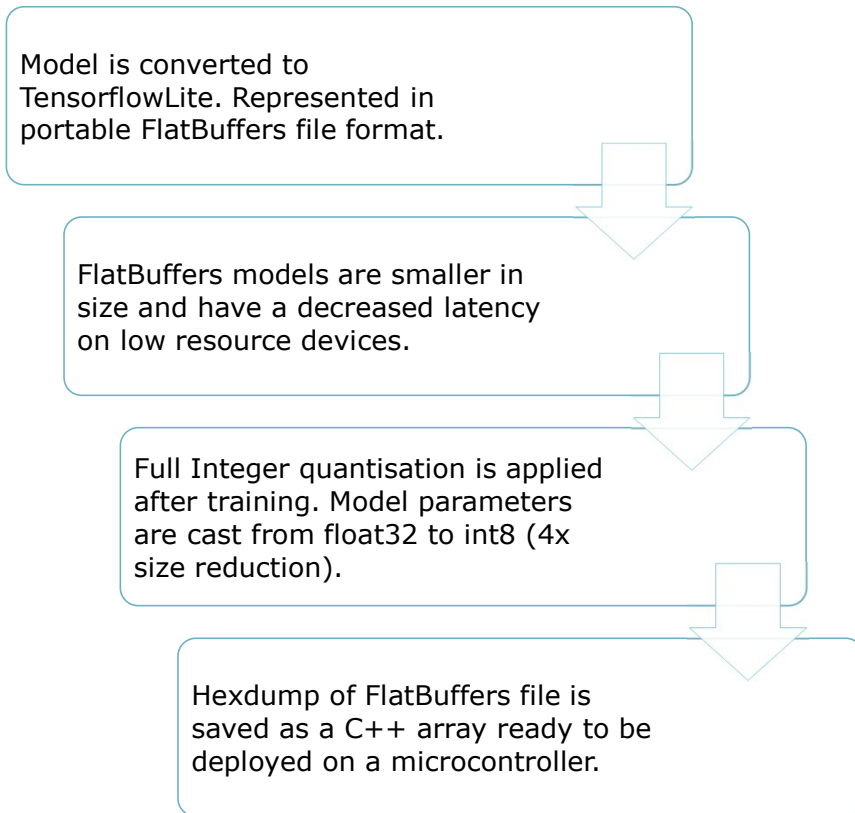
FP = False positive

FN = False negative

Results – F1 Score



Full Integer quantization & deployment to TensorFlow Lite Micro



Future work

Collecting additional
fault data.

Deployment &
inference workflow.

Dealing with flash
size limitations.

Exploration of on-
device training.

References

- [1] Skalski, P. (2021, December 9). *Gentle Dive into Math Behind Convolutional Neural Networks*. Medium. <https://towardsdatascience.com/gentle-dive-into-math-behind-convolutional-neural-networks-79a07dd44cf9>
- [2] Rohrer, B. (2020, February 29). *Convolution in one dimension for neural networks*. <https://E2eml.School/>. https://e2eml.school/convolution_one_d.html
- [3] *1D Convolution*. (2021). Peltarion. <https://peltarion.com/knowledge-center/documentation/modeling-view/build-an-ai-model/blocks/1d-convolution>
- [4] Sugata, T & Yang, C. (2017). Leaf App: Leaf recognition with deep convolutional neural networks. IOP Conference Series: Materials Science and Engineering. 273. 012004. 10.1088/1757-899X/273/1/012004.
- [5] Mozaffari, M. H., & Tay, L.-L. (2020, June 18). *A review of 1d convolutional neural networks toward unknown Substance Identification in Portable Raman spectrometer*. arXiv.org. Retrieved March 21, 2022, from <https://arxiv.org/abs/2006.10575>

Thanks!

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